Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/619,046	HAN ET AL.	
Examiner	Art Unit	-
Khai M. Nguyen	2617	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (attached)	5/18/2007	KN		